WHAT IS CLAIMED IS:

1. A probe block assembly for probing a device under test (DUT), comprising:

a plurality of independent probe blocks each having a set of probes and/or receptacles that mate to a respective mating set of DUT receptacles and/or probes on said DUT;

a probe block frame which floatably holds said plurality of independent probe blocks to allow each said independent probe block to independently float within said probe block frame relative to a predetermined position within said frame.

2. A probe block assembly in accordance with claim 1, wherein:

said plurality of independent probe blocks are positioned such that each of said respective set of probes and/or receptacles of said respective plurality of independent probe blocks are aligned parallel to a like axis of probing.

3. A probe block assembly in accordance with claim 2, wherein said plurality of independent probe blocks are positioned side-by-side within said frame such that each of said respective set of probes and/or receptacles of said respective plurality of independent probe blocks are aligned parallel to one another and to said axis of probing.

4. A probe block assembly in accordance with claim 1, comprising:

an actuator attached to said probe block frame to controllably move said frame to insert and/or remove said sets of probes and/or receptacles of each of said plurality of independent probe blocks to and/or from said respective mating set of DUT receptacles and/or probes on said DUT.

5. A probe block assembly in accordance with claim 1, wherein at least one of said plurality of independent probe blocks comprises self-centering capability that allows said independent probe block to align to said respective mating set of DUT receptacles and/or probes on said DUT.

6. A probe block assembly in accordance with claim 5, wherein said self-centering capability comprises at least one pair of coaxially aligned springs positioned perpendicular to said axis of probing on opposite sides of said independent probe block.

7. A method for probing a plurality of sets of receptacles and/or probes of a device under test (DUT), said plurality of receptacles and/or probes requiring probing parallel to a like probing axis, said method comprising:

independently floating a probe block for each of said plurality of sets of DUT receptacles and/or probes of said DUT within a single probe block frame, each said independently floating probe block having a respective set of probe block probes and/or receptacles that mate to a corresponding set of said plurality of sets of receptacles and/or probes of said DUT;

aligning each said independently floating probe block within said single probe block frame to its corresponding set of said plurality of sets of receptacles and/or probes of said DUT; and

actuating said single probe block frame along said probing axis to respectively engage each said respective set of probe block probes and/or receptacles to its corresponding set of DUT receptacles and/or probes.

8. A method in accordance with claim 7, wherein:

said actuating step is performed with a single actuation motion.

9. A method for assembling a probe block assembly for probing a device under test (DUT), said method comprising:

obtaining a plurality of independent probe blocks each having a set of probes and/or receptacles that mate to a respective mating set of DUT receptacles and/or probes on said DUT; and

independently floating said plurality of independent probe blocks within a single probe block frame relative to a predetermined position within said frame.

10. A method in accordance with claim 9, wherein said step for independently floating said plurality of independent probe blocks within said single probe block frame comprises:

positioning each said plurality of independent probe blocks relative to said predetermined position with said single probe block frame such that when said probe block frame is substantially aligned in a predetermined position relative a device under test, each said respective set of probe block probes and/or receptacles substantially aligns to its respective mating set of DUT receptacles and/or probes on said DUT.